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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10079855	FILING DATE 02/20/2002	CLASS 250	SUBC CLASS	GAU 2373	EXAMINER
**APPLICANTS: Komuro Osamu; Morokuma Hirotsugu; Shishido Chie					
**CONTINUING DATA VERIFIED:					
** FOREIGN APPLICATIONS VERIFIED: JAPAN 2001-249569 08/20/2001					
PLS PUB <input type="checkbox"/> DO NOT PUBLISH <input type="checkbox"/>		RESCIND <input type="checkbox"/>			
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no Verified and Acknowledged Examiner's initials				ATTORNEY DOCKET NO N9450 0046 P046	
TITLE : Process conditions change monitoring systems that use electron beams and related monitoring methods					

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Assistant Examiner	
ISSUE FEE		Total Claims	
Amount Due	Date Paid	Print Claim for O.G.	
		DRAWING	
		Sheets Drwg.	Figs. Drwg.
		Print Fig.	
		Primary Examiner	
<input type="checkbox"/> TERMINAL DISCLAIMER		Application Examiner	
		PREPARED FOR ISSUE	
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